

# FQP7N80C / FQPF7N80C N-Channel QFET MOSFET

800 V, 6.6 A, 1.9 Ω

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### Description

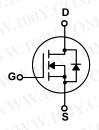
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

- 6.6 A, 800 V,  $R_{DS(on)}$  = 1.9  $\Omega$  (Max) @V<sub>GS</sub> = 10 V,  $I_D$  = 3.3 A
- · Low Gate Charge (Typ. 27 nC)
- Low Crss (Typ. 10 pF)
- · 100% Avalanche Tested







# **Absolute Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	FQP7N80C	FQPF7N80C	Unit	
V <sub>DSS</sub>	Drain-Source Voltage	8	800		
l <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)	6.6	6.6 *	A A	
	- Continuous (T <sub>C</sub> = 100°C)	4.2	4.2 *	Α	
I <sub>DM</sub>	Drain Current - Pulsed (Note 1)	26.4	26.4 *	N.A	
$V_{GSS}$	Gate-Source Voltage	± 30		V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)	580		mJ	
I <sub>AR</sub>	Avalanche Current (Note 1)	6.6		A	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	16.7		mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5		V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)	167	56	W	
	- Derate above 25°C	1.33	0.44	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150		°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300		°C	

<sup>\*</sup> Drain current limited by maximum junction temperature.

#### **Thermal Characteristics**

Symbol	Parameter	FQP7N80C	FQPF7N80C	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	2.25	°C/W	
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	TIV	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W	
		4 1100			

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	800	·		V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	OM.	0.93		V/°C
I <sub>DSS</sub>	7 0.1. 1/15/1 20: 0	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		(1,2-7,	10	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 640 V, T <sub>C</sub> = 125°C	CT.	- FV	100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	- <del>C</del> O		100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$		VI-T	-100	nA
On Cha	racteristics	A.TW WWW.100	Y.U	OM.	IN	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0	COM	5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3.3 A	OOX	1.57	1.9	Ω
9FS	Forward Transconductance	$V_{DS} = 50 \text{ V}, I_D = 3.3 \text{ A}$ (Note 4)	100	5.5	<b>11-</b>	S
<b>Dynam</b> i C <sub>iss</sub>	mic Characteristics  Input Capacitance  Vac = 25 V Vac = 0 V		N.10	1290	1680	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	W. 2	120	155	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1.0 (vii 12		10	13	pF
001.	ng Characteristics	ON COMITY Y	INV	1.100	V.CO	1.1
t <sub>d(on)</sub>	Turn-On Delay Time	V - 400 V I - 6.6 A		35	80	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, I_{D} = 6.6 \text{ A},$ $R_{G} = 25 \Omega$	44-	100	210	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	NG - 20 32	MA	50	110	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)	- T.	60	130	ns
$Q_g$	Total Gate Charge	V <sub>DS</sub> = 640 V, I <sub>D</sub> = 6.6 A,		27	35	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V	\	8.2	1700	nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		11	700	nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings		WW	W.10	OY.C
Is	Maximum Continuous Drain-Source Diode Forward Current			411	6.6	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				26.4	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.6 A		1	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 6.6 \text{ A,}$	N	650	1.47	ns

 $dI_F / dt = 100 A/\mu s$ 

(Note 4)

7.0

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# $Q_{rr}$ Notes:

**Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 25mH,  $I_{AS}$  = 6.6A,  $V_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C 3.  $I_{SD}$  ≤ 8A, di/dt ≤ 200A/ $\mu$ s,  $V_{DD}$  ≤ BV $_{DSS}$ , Starting  $T_{J}$  = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s, Duty cycle ≤ 2%

Reverse Recovery Charge

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- WWW.100Y.COM.TW 5. Essentially independent of operating temperature

 $\mu$ C

# **Typical Characteristics**

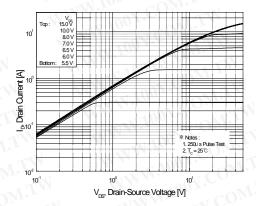


Figure 1. On-Region Characteristics

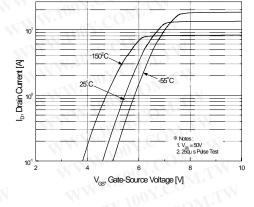


Figure 2. Transfer Characteristics

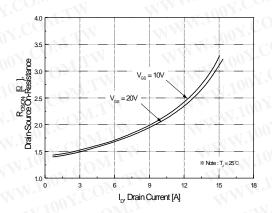


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

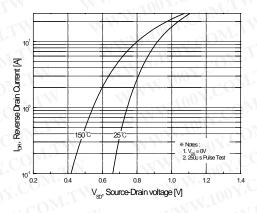


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

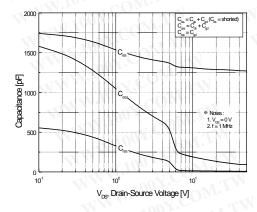


Figure 5. Capacitance Characteristics

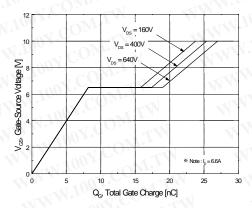


Figure 6. Gate Charge Characteristics

1. V<sub>cs</sub> = 10 V 2. l<sub>c</sub> = 3.3 A

150

100

T,, Junction Temperature [°C]

vs Temperature

# Typical Characteristics (Continued)

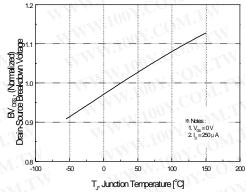
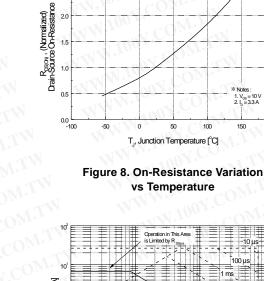


Figure 7. Breakdown Voltage Variation vs Temperature



2.0

I<sub>D</sub> Drain Qurrent [A] 10<sup>2</sup> V<sub>DS</sub>, Drain-Source Voltage [V]

Figure 9-1. Maximum Safe Operating Area for FQP7N80C

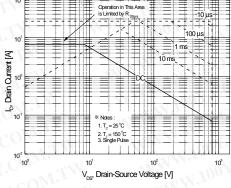


Figure 9-2. Maximum Safe Operating Area for FQPF7N80C

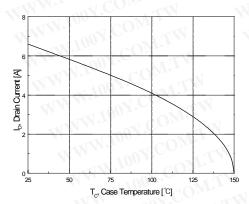


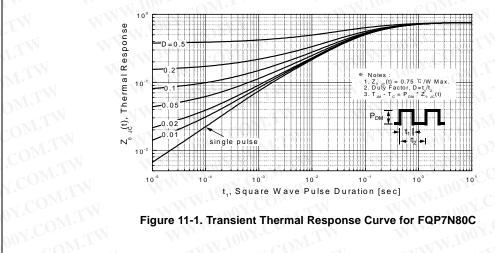
Figure 10. Maximum Drain Current vs Case Temperature

## Typical Characteristics (Continued)

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Figure 11-1. Transient Thermal Response Curve for FQP7N80C

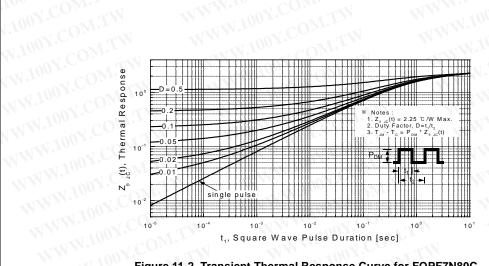
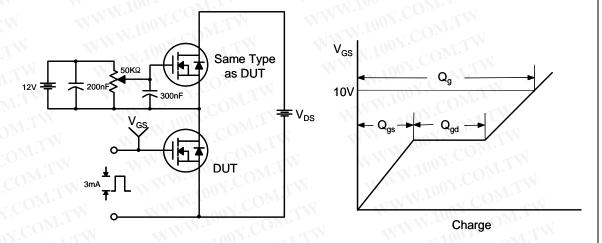
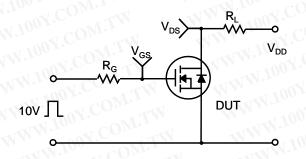


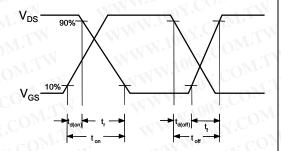
Figure 11-2. Transient Thermal Response Curve for FQPF7N80C WWW.100Y

#### **Gate Charge Test Circuit & Waveform**

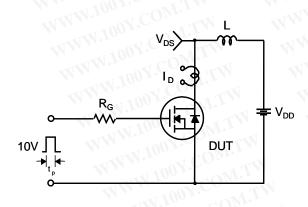


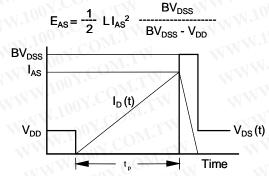
## **Resistive Switching Test Circuit & Waveforms**



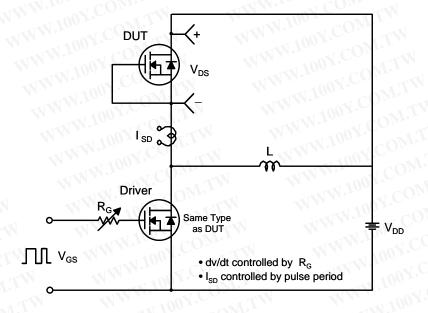


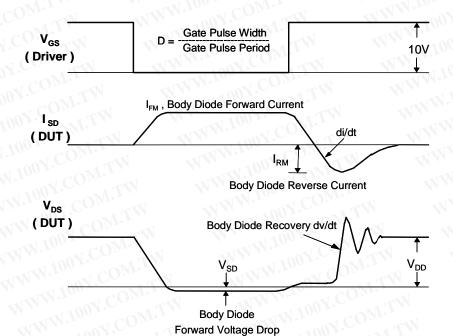
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

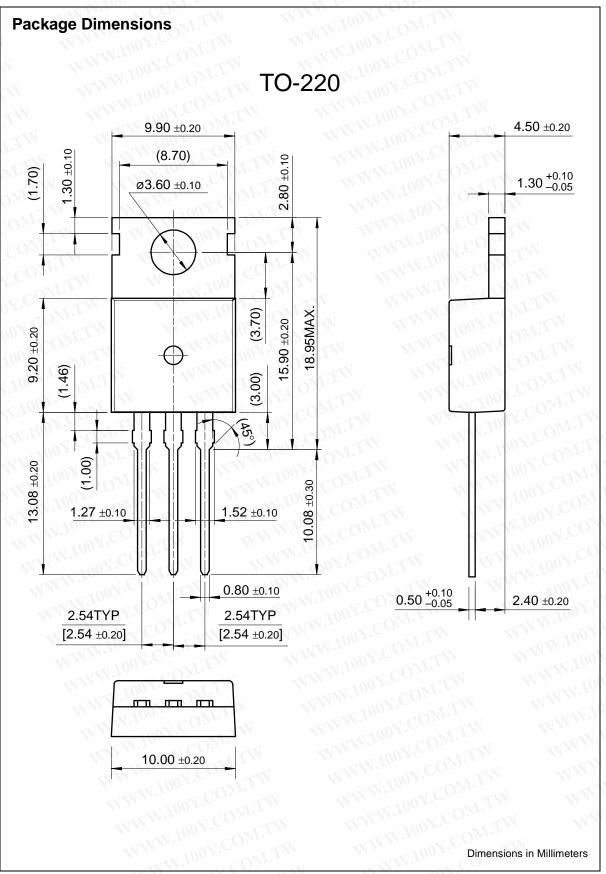


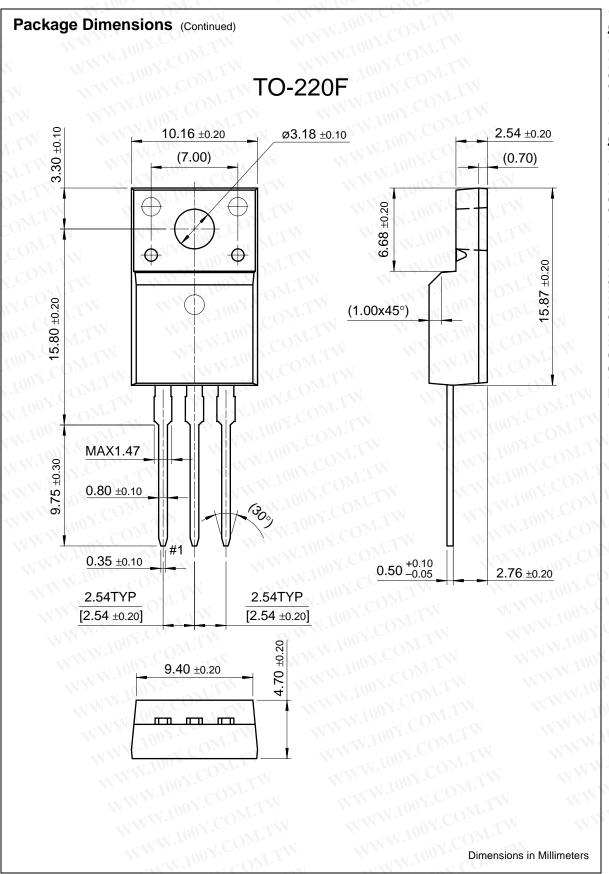


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms











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